Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/602,458	JOHNSON ET AL.	
Examiner	Art Unit	
Thomas K. Pham	2121	

SEARCHED					
Class	Subclass	Date	Examiner		
700	28	12/20/2005	TP		
700	29	12/20/2005	TP		
700	30	12/20/2005	TP		
700	31	12/20/2005	TP		
700	32	12/20/2005	TP		
- 700	47	12/20/2005	TP		
700	48	12/20/2005	TP		
700	173	12/20/2005	TP		
701	58	12/20/2005	TP		
701	59	12/20/2005	TP		
701	60	12/20/2005	TP		
701	63	12/20/2005	TP		
701	38	12/20/2005	TP		

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
					
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SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
EAST (USPT, PGPub, OCR, JPO, EPO, DERW)	12/20/2005	TP
700/28-32,47,48,173 701/58-60,63,38 (see search history printout)	12/20/2005	TP
Double patenting checked with pat 6,618,631	12/20/2005	TP
NPL - IEEE XPlore attached	7/27/2006	TP